

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Charles W. Schietinger et al.
Title: Optical Techniques for Measuring Layer Thicknesses and Other
Surface Characteristics of Objects Such as Semiconductor Wafers
Application No.: Unassigned Filing Date: Herewith
Examiner: Unassigned Group Art Unit: Unassigned
Docket No.: LUXT.118US2 Conf. No.: Unassigned

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION OF FORMAL DRAWINGS

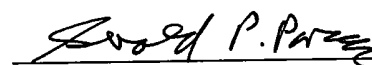
Dear Sir:

Applicants submit fifteen (15) sheets of formal drawings, consisting of Figures 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16A, 16B, 17, 18, 19, 20, 21A, 21B, 22, 23, in the above-named application. If there are any questions regarding these drawings, please call the undersigned at (415) 318-1160.

**EXPRESS MAIL LABEL
NO:**

EV321716457US

Respectfully submitted,



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September 26, 2003
Date

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